

Vishay Siliconix

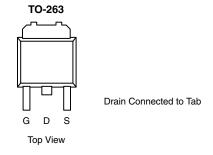
# P-Channel 80-V (D-S) MOSFET

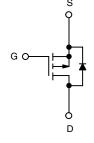
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$r_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>b</sup>	Q <sub>g</sub> (Typ)		
- 80	0.0111 at V <sub>GS</sub> = - 10 V	- 110	113 nC		

#### **FEATURES**

• TrenchFET® Power MOSFET







Ordering Information: SUM110P08-11 (Lead (Pb)-free)

P-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	- 80	V		
Gate-Source Voltage	V <sub>GS</sub>	± 20			
	T <sub>C</sub> = 25 °C		110 <sup>a</sup>		
Continuous Drain Current (T = 150 °C)	T <sub>C</sub> = 125 °C		71		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	23.5 <sup>b, c</sup>		
	T <sub>A</sub> = 125 °C		13.6 <sup>b, c</sup>		
Pulsed Drain Current		I <sub>DM</sub>	- 120	A	
0 11 0 0 0 1	T <sub>C</sub> = 25 °C		110 <sup>a</sup>		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	- 9 <sup>b, c</sup>	7	
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	- 75		
Single-Pulse Avalanche Energy	L = U.1 IIII	E <sub>AS</sub>	281	mJ	
	T <sub>C</sub> = 25 °C		375		
Maximum Power Dissipation	T <sub>C</sub> = 125 °C	В	125	w	
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	13.6 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 125 °C		4.5 <sup>b, c</sup>		
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 sec	$R_{thJA}$	8	11	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	0.33	0.4	C/VV	

a. Package limited.b. Surface Mounted on 1" x 1" FR4 board.

d. Maximum under Steady State conditions is °C/W.

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Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 80			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 85		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	10 = 250 μΛ		7.0			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 2		- 4	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -80 V, V <sub>GS</sub> = 0 V			- 1		
		V <sub>DS</sub> = - 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 175 °C			- 500	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 10 \text{ V}, V_{GS} = -10 \text{ V}$	120			Α	
Drain-Source On-State Resistance <sup>a</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 20 A		0.092	0.0111	Ω	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 20 A		80		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			11500		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = 0 V, f = 1 MHz		790			
Reverse Transfer Capacitance	C <sub>rss</sub>			700			
Total Gate Charge	$Q_g$			185	280	nC	
Gate-Source Charge	$Q_{gs}$	V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 110 A		40			
Gate-Drain Charge	$Q_{gd}$			45			
Gate Resistance	$R_{g}$	f = 1 MHz		3.6		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			25	40	- ns	
Rise Time	t <sub>r</sub>	$V_{DD} = -40 \text{ V}, R_{L} = 0.36 \Omega$		410	620		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong -110 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		145	220		
Fall Time	t <sub>f</sub>			470	710		
Drain-Source Body Diode Characteristic	s			1			
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 110		
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 120	A	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 20 A		- 0.8	- 1.5	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			65	100	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 20 A, di/dt = 100 A/μs, T <sub>.I</sub> = 25 °C		135	205	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$_{1F} = -20 \text{ A}, \text{ u/ut} = 100 \text{ A/}\mu\text{s}, \text{ I}_{J} = 25 \text{ C}$		43		nc	
Reverse Recovery Rise Time	t <sub>b</sub>			22		ns	

#### Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

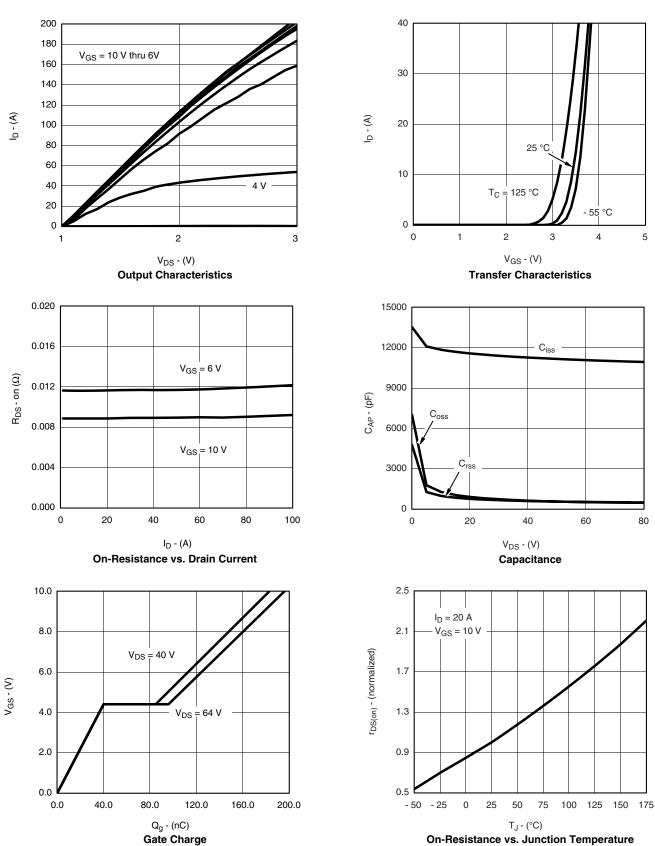
a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$ 

b. Guaranteed by design, not subject to production testing.



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#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

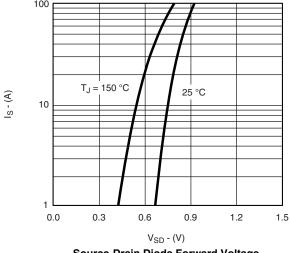


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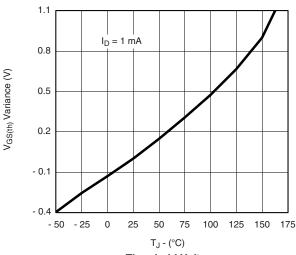
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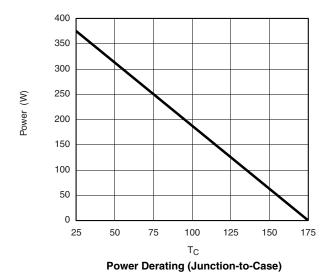
## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Source-Drain Diode Forward Voltage

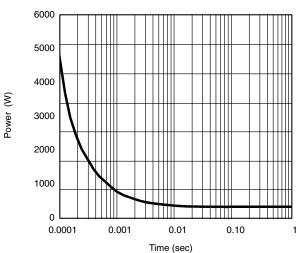


**Threshold Voltage** 

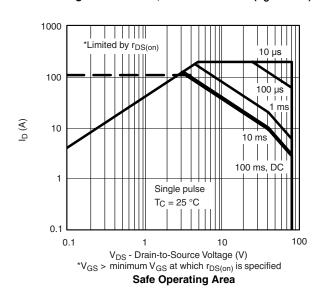


0.05 0.04 0.03 0.02 0.01 0.01 0.01 0.00 0 2 4 6 8 10 V<sub>GS</sub> - (V)

On-Resistance vs. Gate-to-Source Voltage



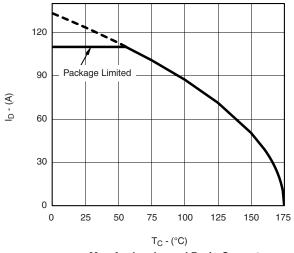
Single Pulse Power, Junction-to-Case ( $T_C = 25$  °C)

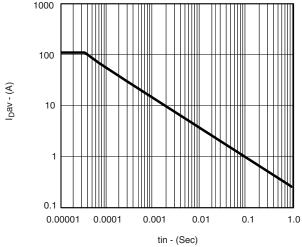




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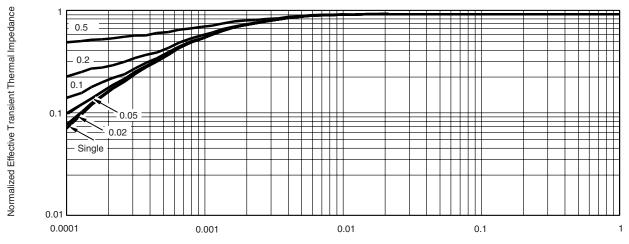
#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





Max Avalanche and Drain Current vs. Case Temperature

**Avalanche Current vs. Time** 



Normalized Thermal Transient Impedance, Junction-to-Case

\*The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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